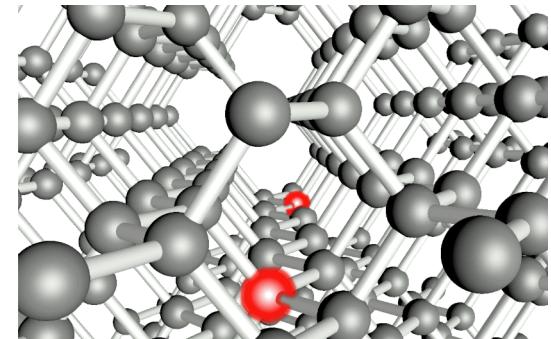
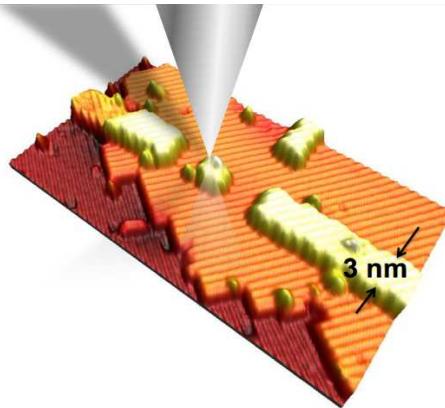
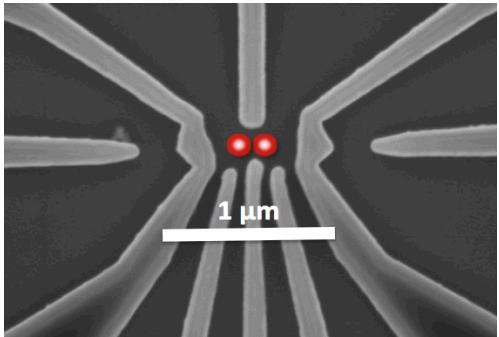


Exceptional service in the national interest

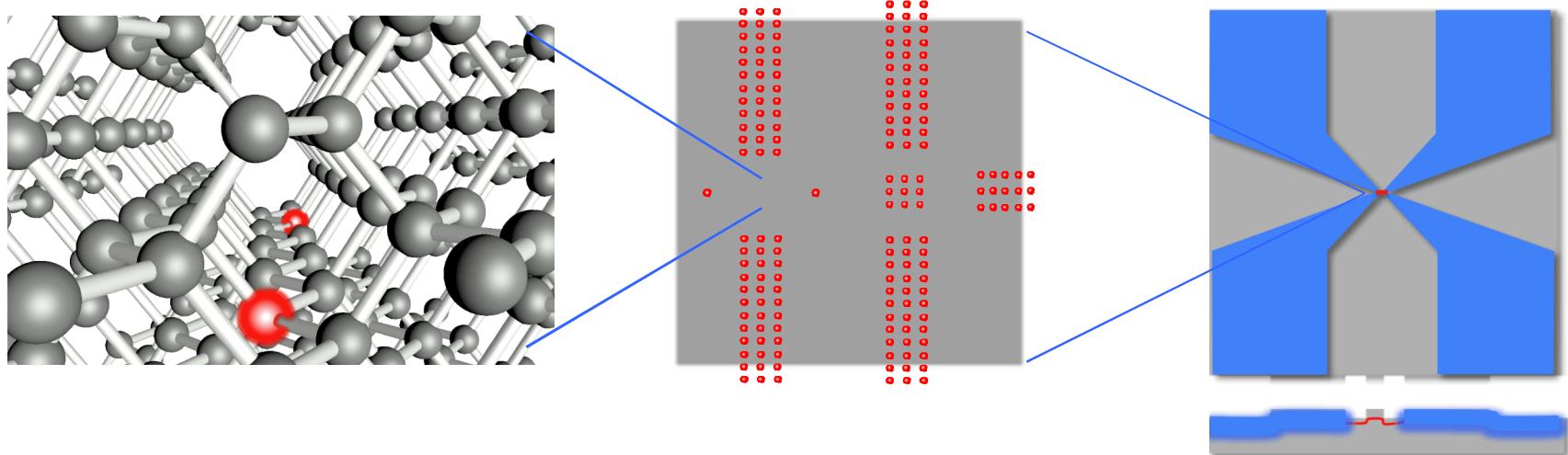


Donor charge qubits via STM assisted fabrication

Ezra Bussmann (ebussma@sandia.gov) J. Dominguez, S.Carr, T.-M. Lu, E. Nielsen, R. Rahman, T. Jacobson, W. Witzel, G. Ten Eyck, M. P. Lilly, M. S. Carroll

We want to make atomic-precision devices

- Goal: A Sandia capability to fabricate atomic-precision donor qubits in Si



Atomic-scale
circuit elements
-individual dopants
positioned with atomic
precision

Integrated in
nanoscale
electronics
-gates,
charge sensors

Integrated in
conventional
electronics
-wires, contacts

- Over about 12 years, Michelle Simmons (UNSW CQC2T Australia) has demonstrated the atomic-precision fabrication techniques and device elements
- Technique: Combine ultrahigh vacuum scanning tunneling microscopy (STM) lithography and conventional Si fabrication techniques

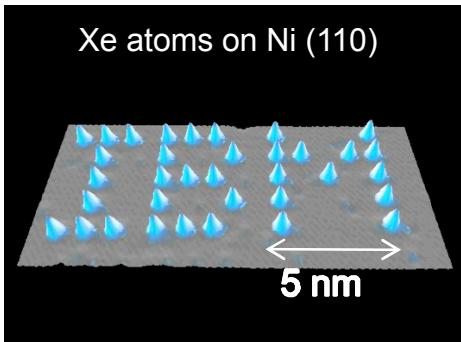
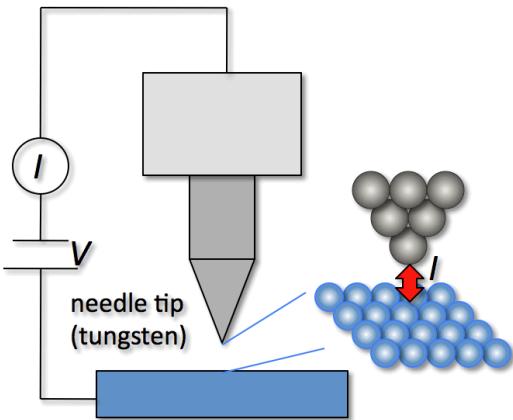
Talk overview



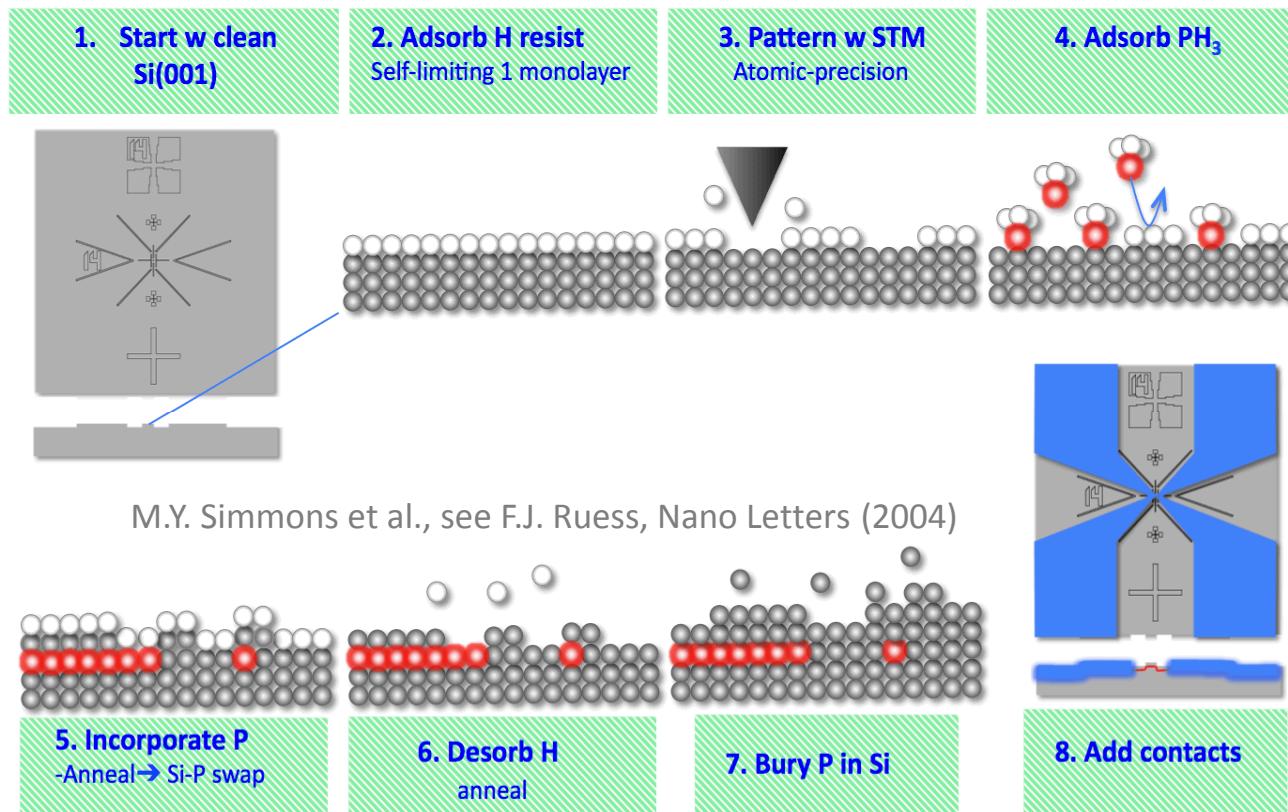
- I. Quick review of Scanning Tunneling Microscopy (STM) Fabrication
- II. Review of progress report at 2nd EAB (October 2011)
- III. New results since the 2nd EAB**
 - Completed new cleanroom lab for STM assisted fab*
 - Reproduced Simmons qubit fabrication steps in lab*
 - Fabricated initial macroscopic test devices*
 - Performed design & modeling of qubit*
- IV. Present work: demonstrate a working atomic-precision device

STM assisted fab overview

- STM : an atomic resolution surface imaging and manipulation tool



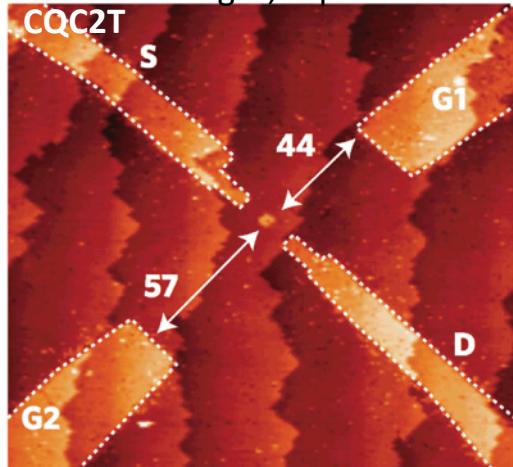
D.M. Eigler et al. *Nature* (1990)



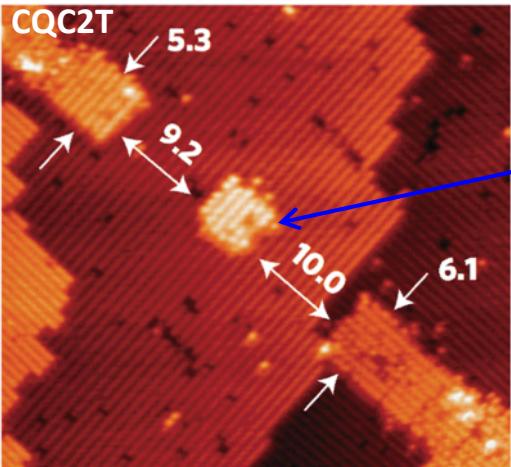
Atomic-precision devices have been demonstrated

- **Example: tunable quantum dot** M. Y. Simmons et al. Nature Nano (2010)

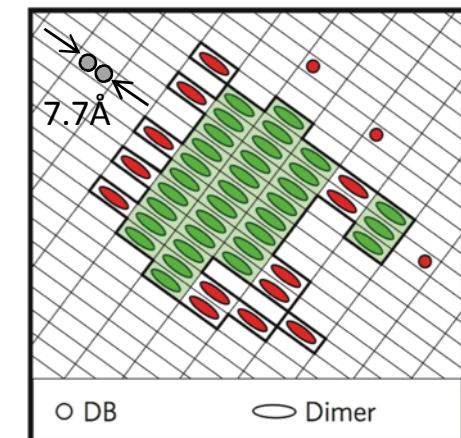
STM images, top view



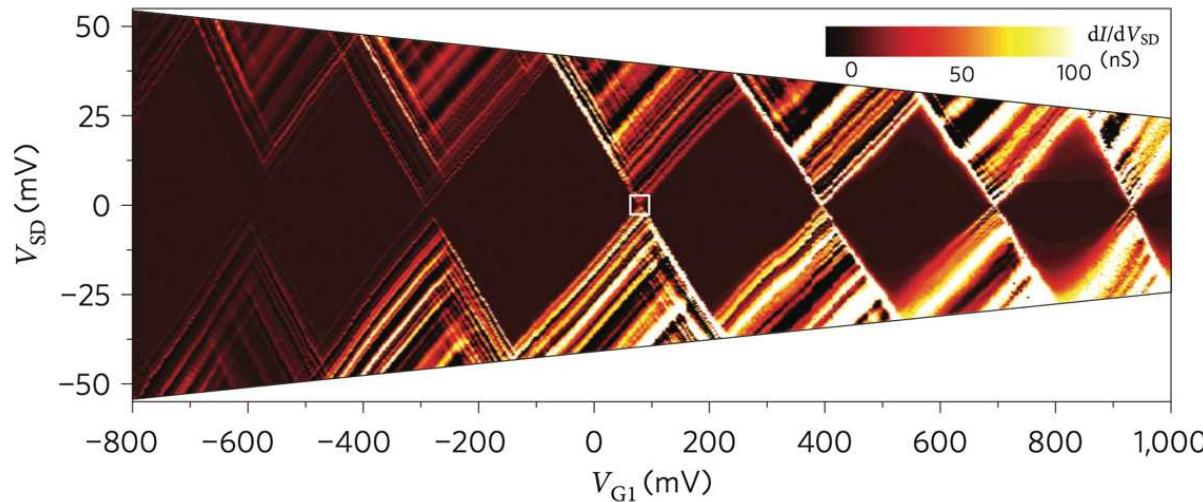
units are nanometers



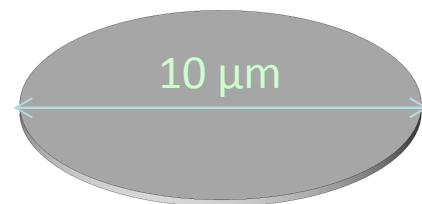
Effective window for P
surface atomic lattice



Coulomb blockade and electronic structure of the dot

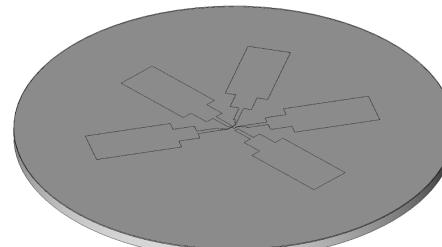
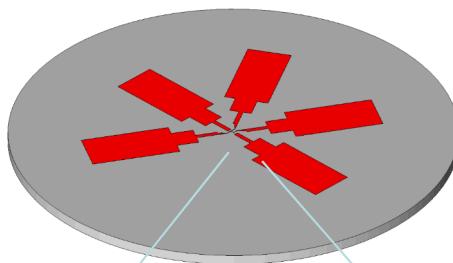


Target device: donor charge qubit

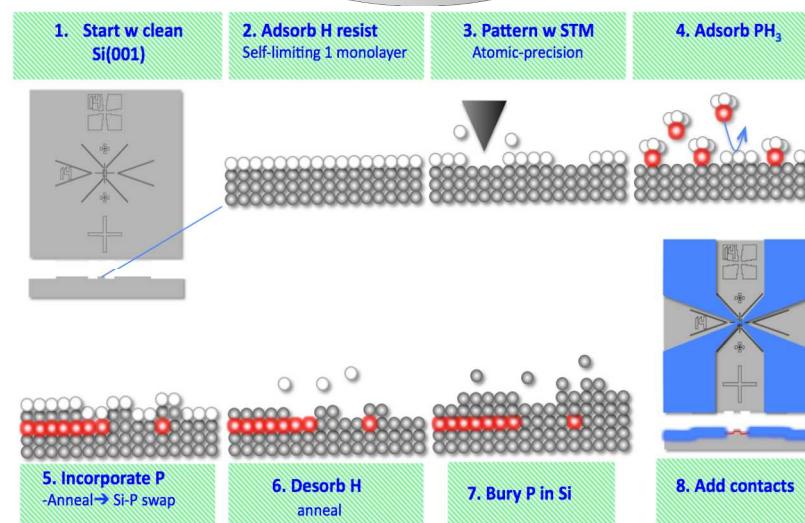
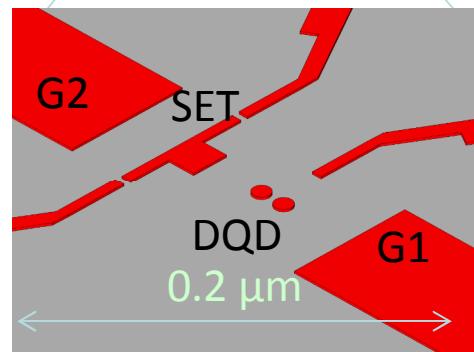
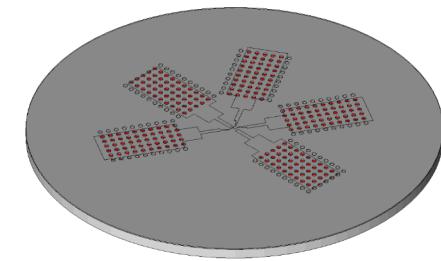


1. Clean Si w etched alignment markers (not shown)

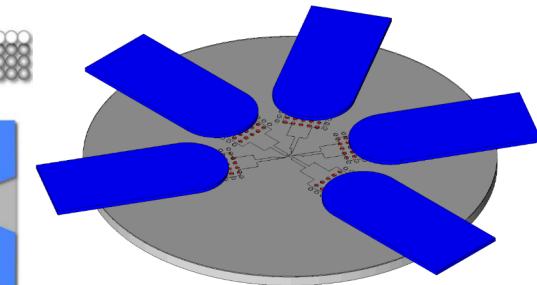
2. Perform STM process then bury device in 25-nm-thick epi-Si



3. Align & drill vias thru epi-Si



4. Form metal contacts



- Objective: demonstrate fabrication of a donor charge qubit

Milestones for STM fab



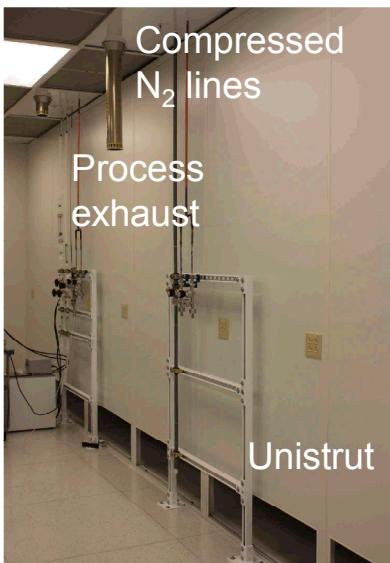
- Year 1
 - Recover old STM chamber outside of clean room for non-toxic gas experiments
 - Design clean room STM (includes phosphine capability)
 - Build clean room STM (Including PH3, labspace, etc)
 - Show clean hydrogen terminated surface and local removal with STM tip
- Year 2
 - Establish capability to pattern large areas (long tip lifetime)
 - Connection to large area contacts (n+ or Al spike)
 - Silicon encapsulation of phosphorus
 - Incorporation of phosphorus on surface
 - Demonstrate initial transport test devices (wires)
 - Demonstrate single donor placement
- Year 3
 - Demonstrate two donor placement
 - Demonstrate transport through double donor
 - Develop charge sensor for two donor system
 - Demonstrate qubit

Milestones for STM fab

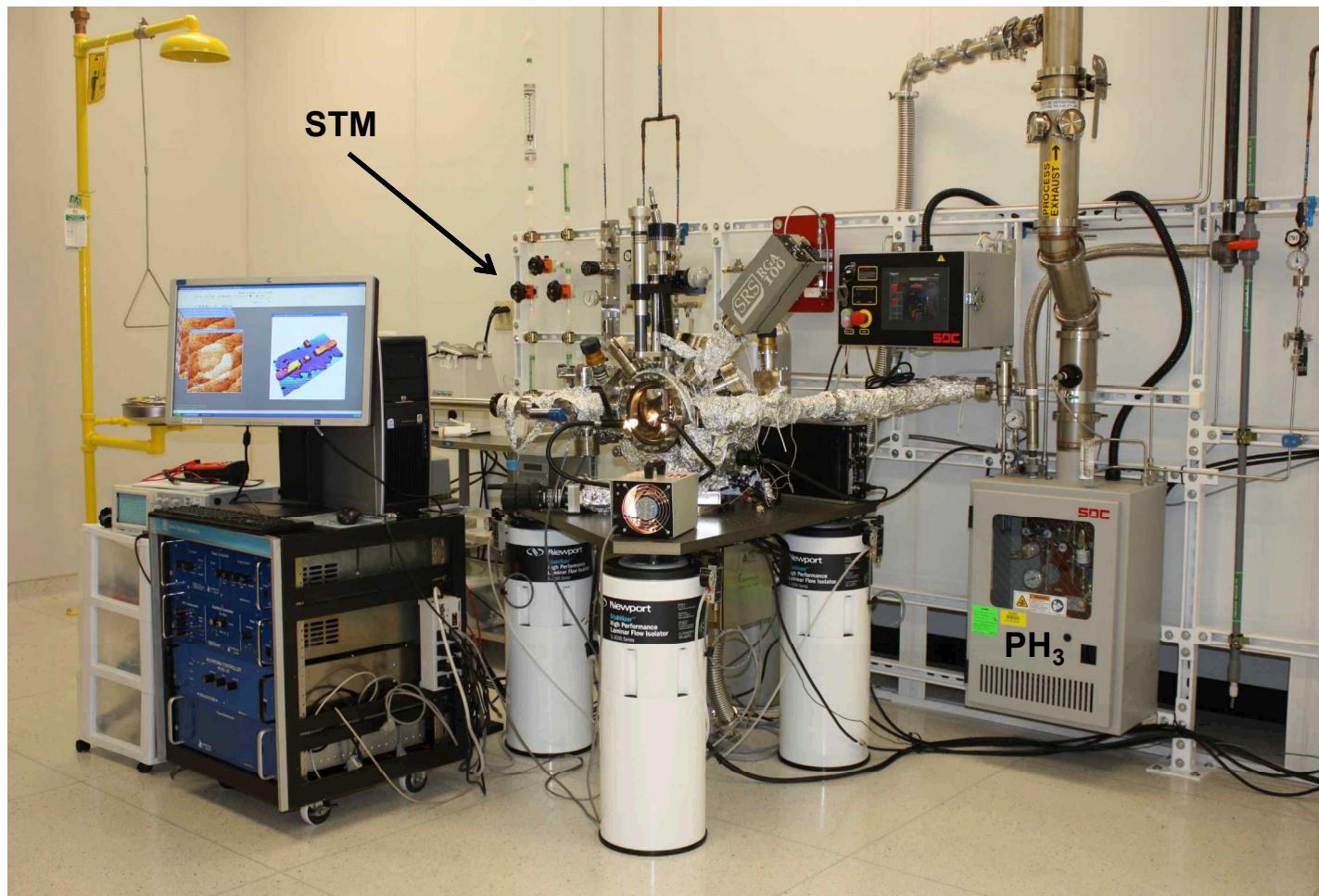


- Year 1
 - Recover old STM chamber outside of clean room for non-toxic gas experiments
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 - ✓ Build clean room STM
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 - Establish capability to pattern large areas (long tip lifetime)
 - ✓ Connection to large area contacts (n+ or Al spike)
 - ✓ Silicon encapsulation of phosphorus
 - ✓ Incorporation of phosphorus on surface
 - ✓ Demonstrate initial transport test devices (wires) (Macroscopic Hall effect devices)
 - Demonstrate single donor placement
- Year 3
 - Demonstrate two donor placement
 - Demonstrate transport through double donor
 - Develop charge sensor for two donor system
 - Demonstrate qubit

Completed new lab in cleanroom



8/2011



5/2012

- We now have two labs and two working STMs for donor device fabrication

Completed new STM for Si fab process

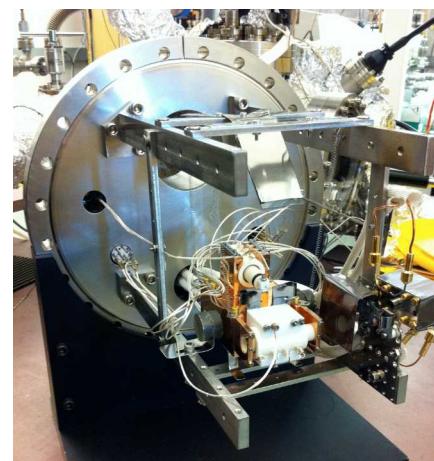
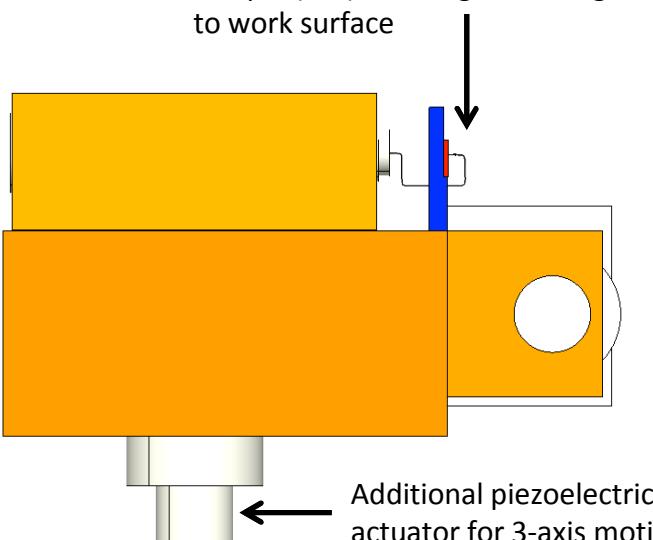


(mid-2011-3/2012)



11/2011

STM probe wraps around
sample (red) allowing line-of-sight
to work surface



1/2012

New STM head w/ X-Y-Z motion and
line-of-sight to sample

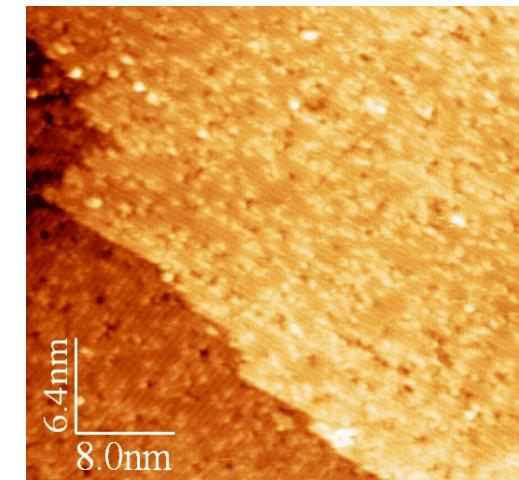
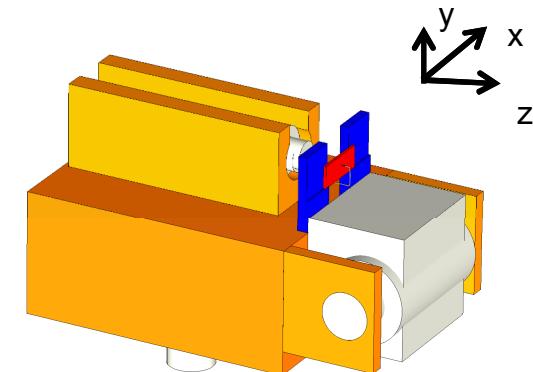


Image obtained with new STM
near-atomic resolution (3/2012)

Progress on fabrication steps

2nd EAB

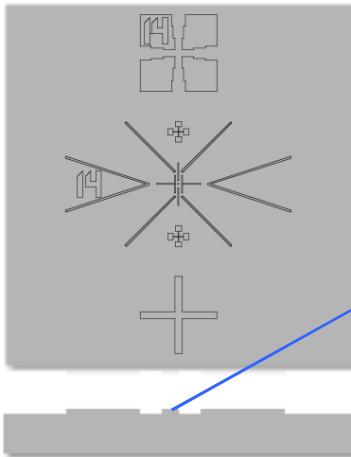
1. Start w clean
Si(001)

2. Adsorb H resist
Self-limiting 1 monolayer

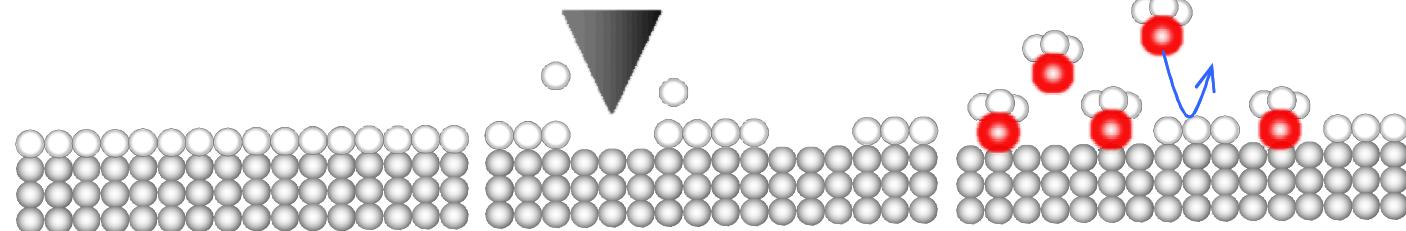
3. Pattern w STM
Atomic-precision

Testing PH₃
system

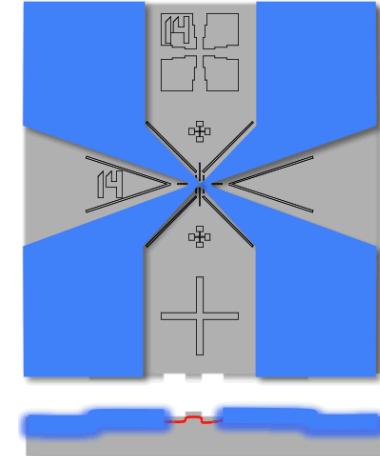
4. Adsorb PH₃



Etched alignment marks
J. Dominguez



Al depo+lift off
J. Dominguez



5. Incorporate P
-Anneal \rightarrow Si-P swap
-H resist constrains P

6. Desorb H
anneal

7. Bury P in Si

8. Add contacts

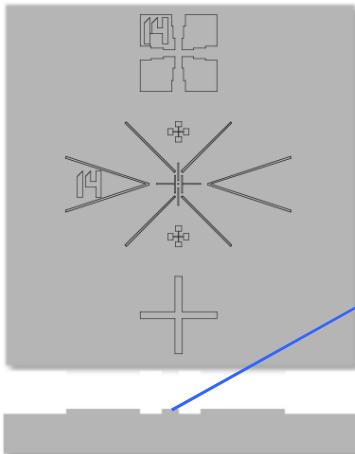
Progress on fabrication steps

1. Start w clean
Si(001)

2. Adsorb H resist
Self-limiting 1 monolayer

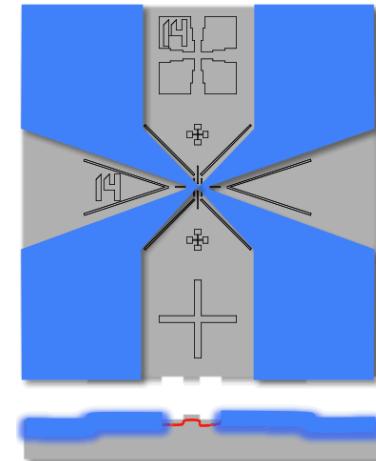
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Etched alignment marks
J. Dominguez

Al depo+lift off
J. Dominguez



5. Incorporate P
-Anneal \rightarrow Si-P swap

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anneal

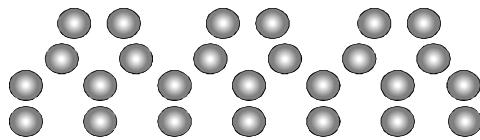
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8. Add contacts

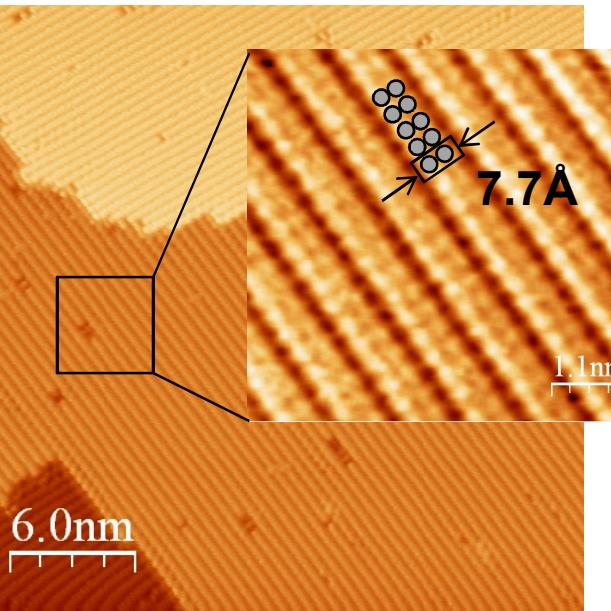
Progress on fabrication steps

1. Prepare clean Si(001) (10-11/2010)

side views

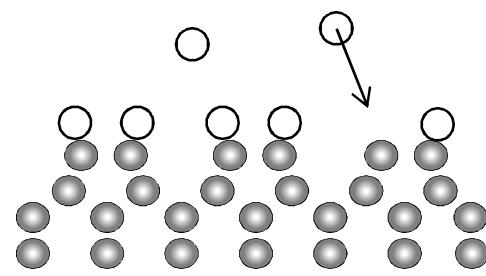


top views

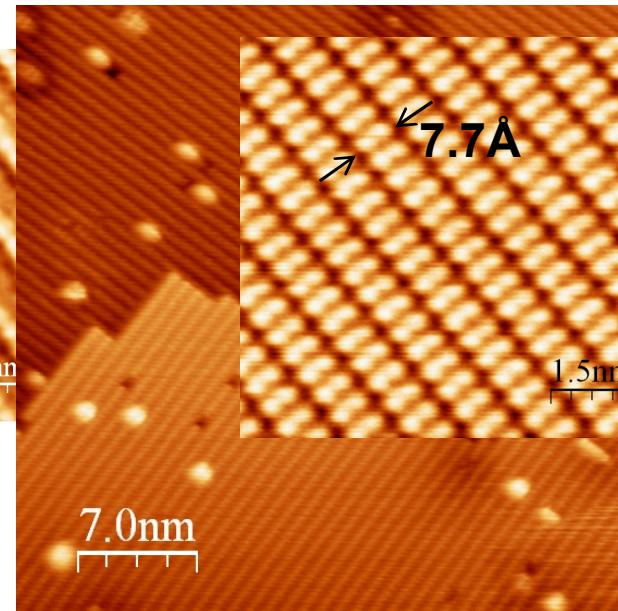
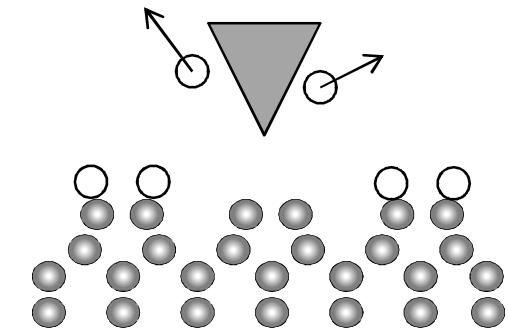


Si(100)-2x1

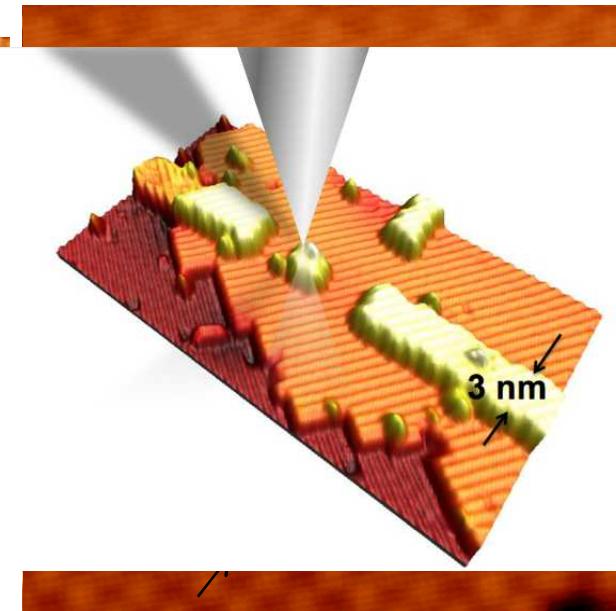
2. Low-defect H resist layers (11/2010)



3. Atomic-precision windows in resist (12/2010)



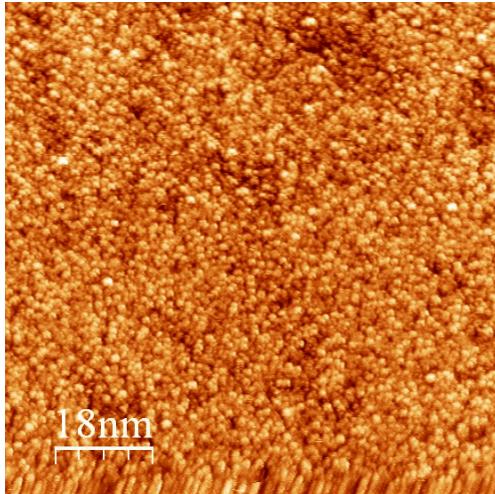
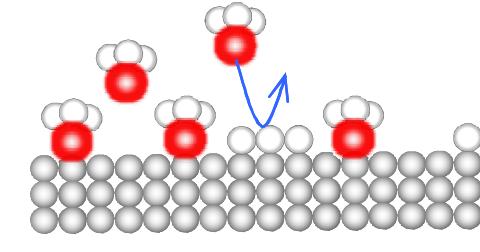
Si(100)-2x1-monohydride



Progress on fabrication steps

4. Adsorb PH₃ (1/2012)

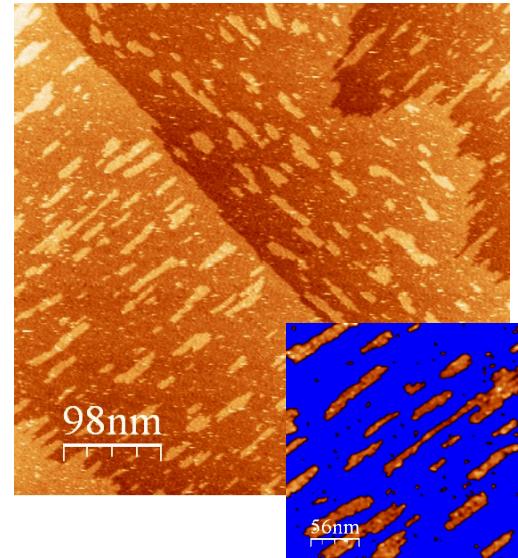
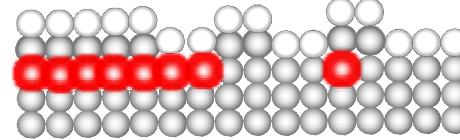
- Expose to PH₃ gas



Mixed phase of H/PH_x
On Si surface

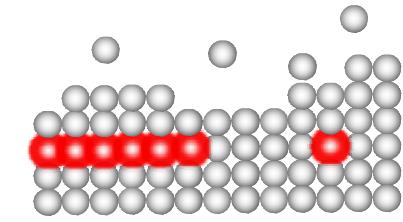
5. Incorporate P into Si (2-4/2012)

- Anneal 350C-500C

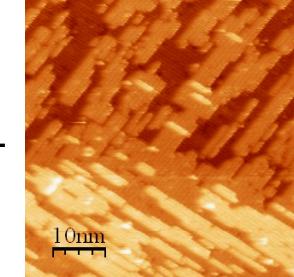


P incorporates into
Si → Si ejected to surface
Forming Si islands

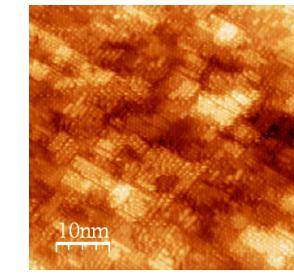
6. Bury device in epi-Si (1/2011-2/2011)



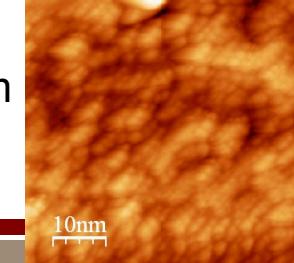
0.7 ML



40 ML
~5 nm



80 ML
~10 nm



Thicker Si growth → rougher surface

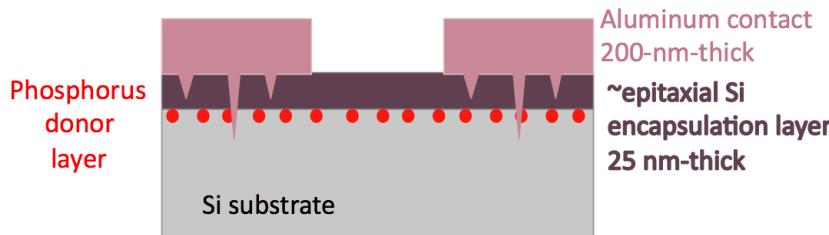
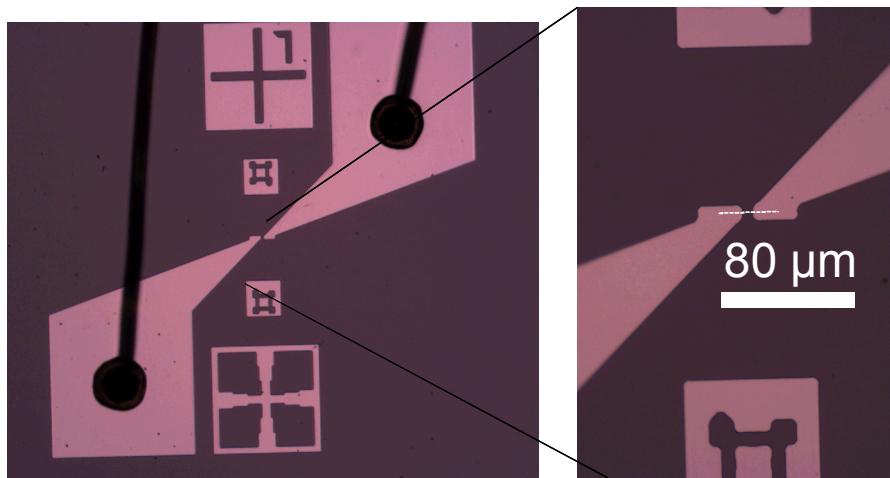
Fabricated initial test devices

(3/2012 - 5/2012)



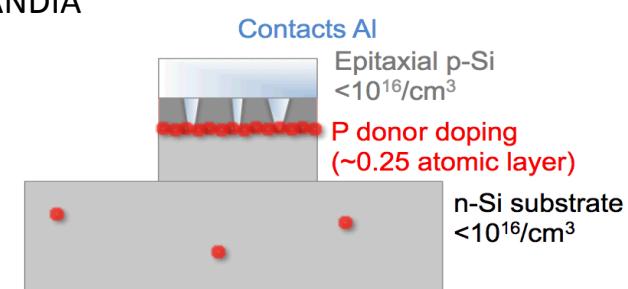
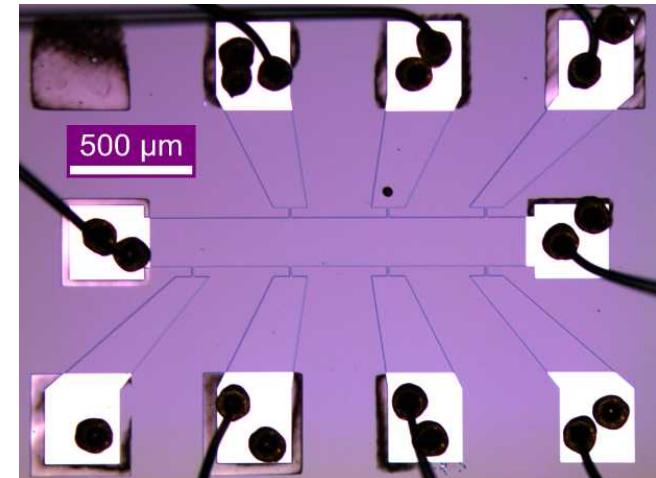
- Fabricated and characterized two types of diagnostic devices verifying successful incorporation, encapsulation, and connection to highly doped P donor layer

Two-contact device



Device cross section schematic

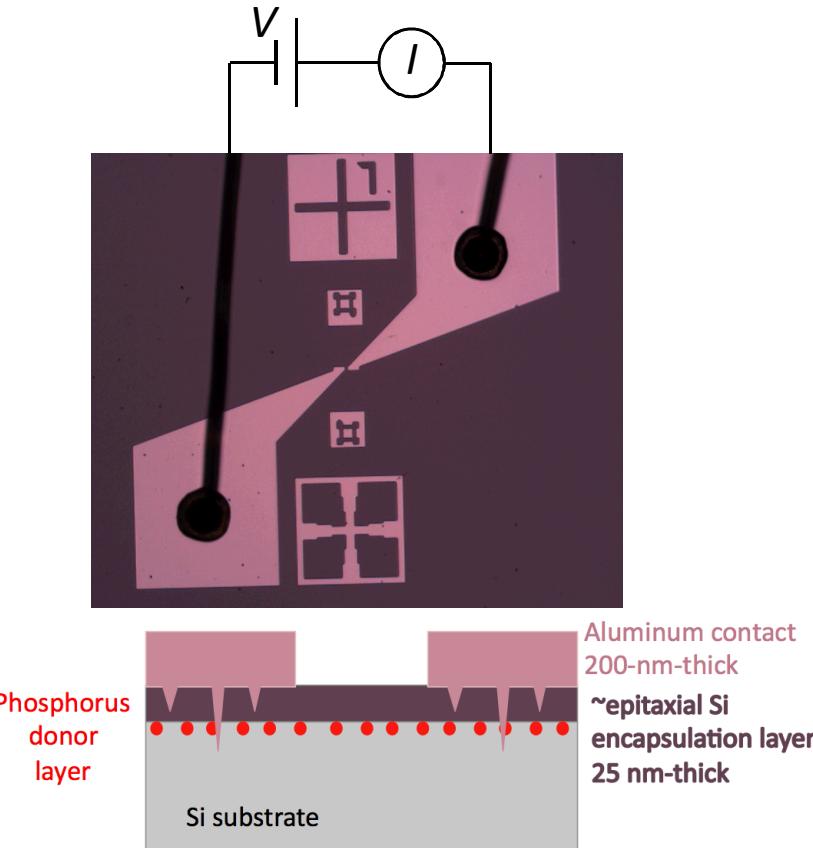
Trench isolated Hall device



Device cross section schematic

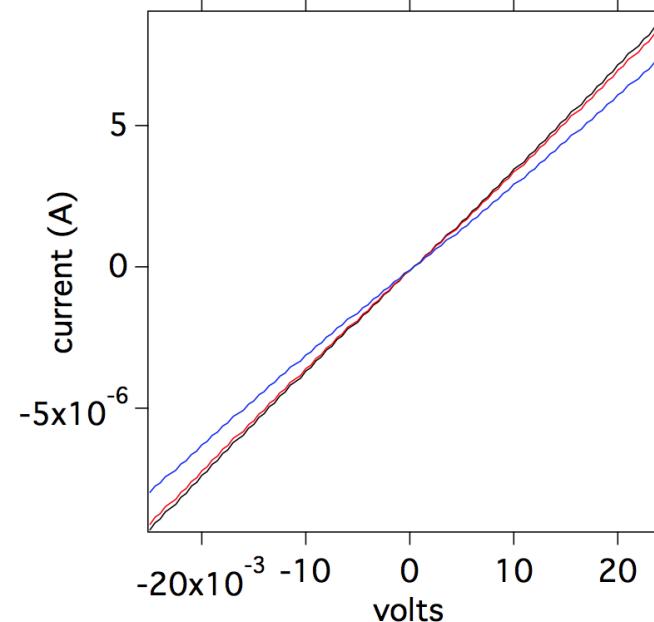
Characterized initial test devices

(3/2012 - 5/2012)



Device cross section schematic

Current vs voltage measurements for three devices at $T=4K$

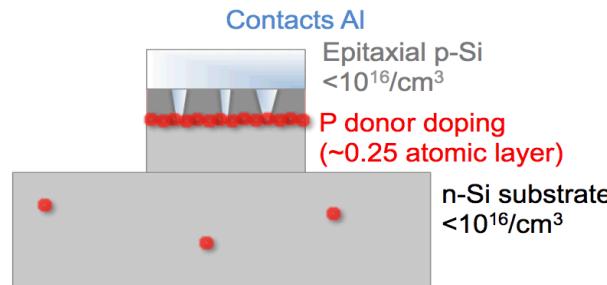
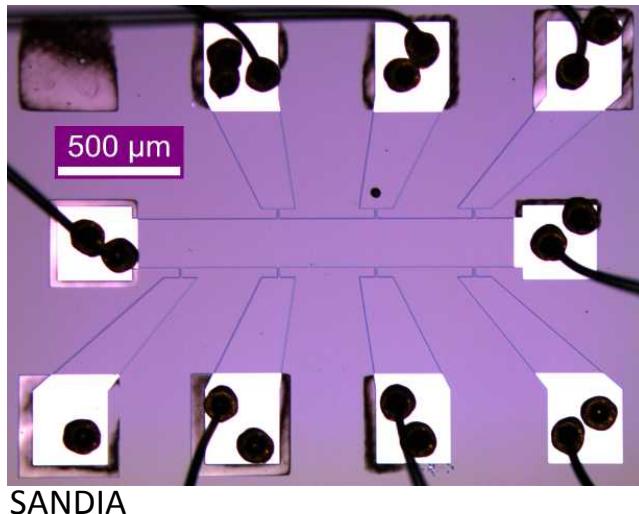


- **Ohmic conduction at 4K shows successful fab & connection to highly doped donor layer**
- **Typical resistances of 2-6 k Ω are similar to Simmons results (Nano Lett. 2004)**

Characterized initial transport devices

(4/2012 - 5/2012)

Trench isolated Hall device



- Extract e- density & mobility from longitudinal R_{xx} and transverse R_{xy} Hall resistance

Electron density and mobility at T=4K

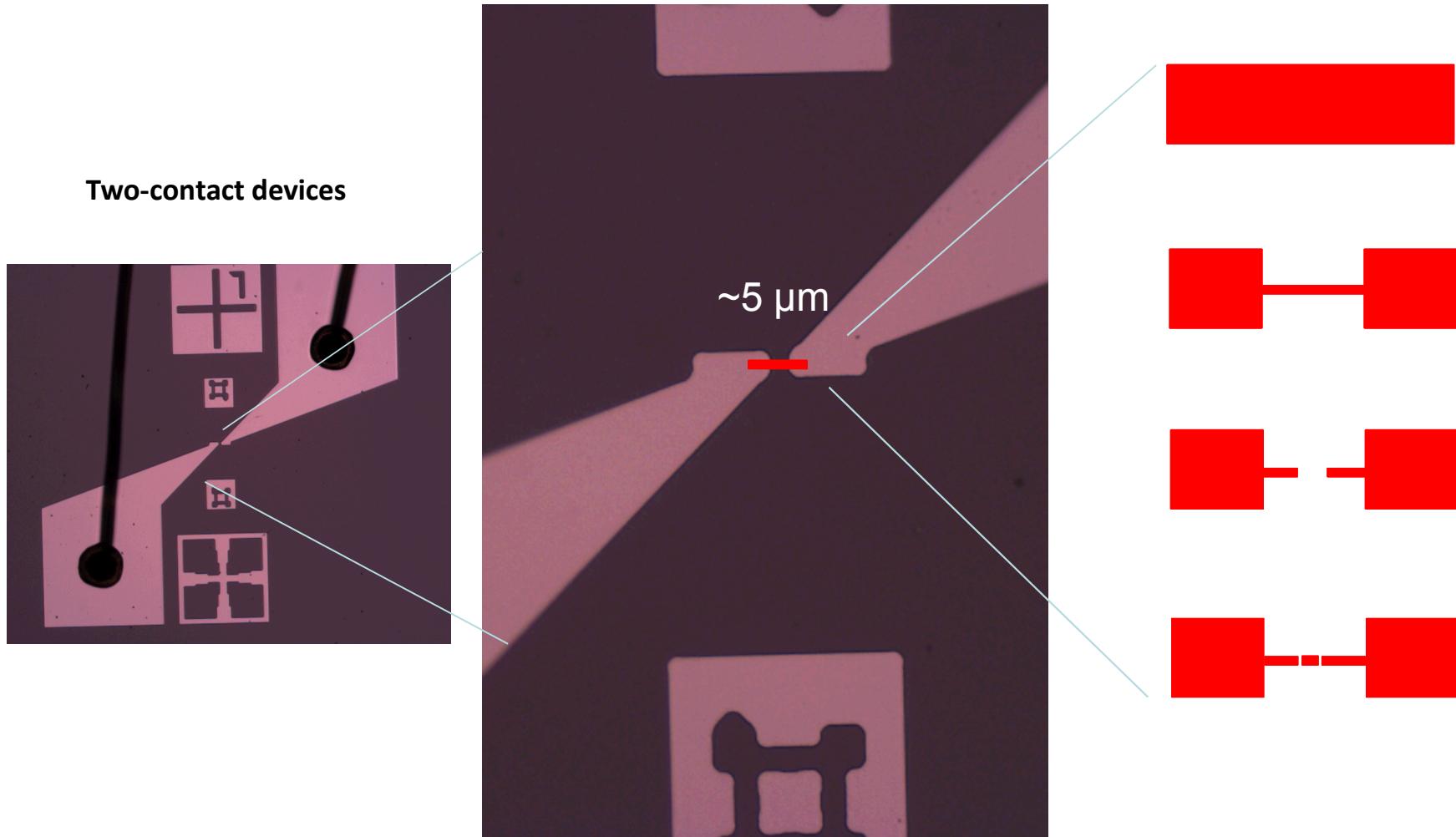
Device	e- density n_e $10^{14}/\text{cm}^2$	e- mobility cm^2/Vs
1	0.7	127
2	0.7	143
3	1.2	122

- Similar Hall effect devices from Simmons yielded $n = 1.2-1.7 \times 10^{14}/\text{cm}^2$ mobility $<100 \text{ cm}^2/\text{Vs}$

- Donor and electron density sufficient for atomic precision devices
- Next step: implement complete atomic-precision fab technique

Present work: complete nano-device

- Do all fab steps sequentially to produce patterned nanoscale device (a milestone for this year)



- After demonstrating two-contact test devices, we will try qubit structures (3+ contacts)

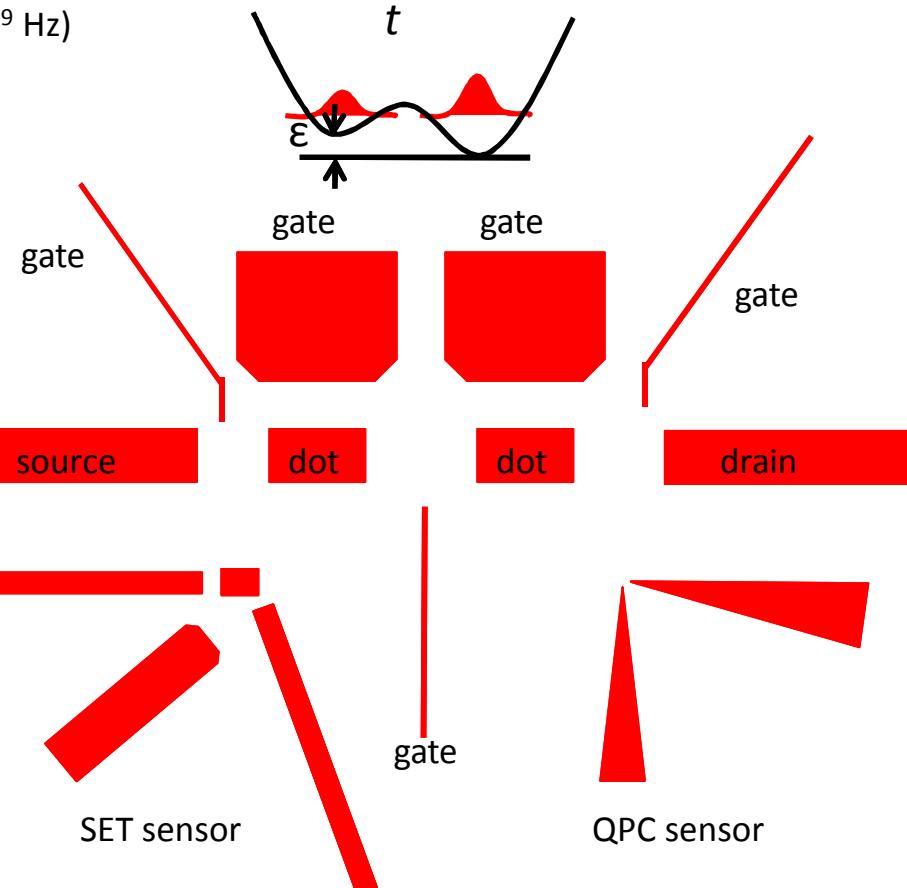
Preparing initial qubit designs

(4/2012-6/2012)

Brainstorm on what we need for qubit

1. Tunable e- occupation (few electron) and relative energy ϵ
2. Tunable tunnel barriers (ideally tunnel rates from 0 to $>10^9$ Hz)
3. A charge sensor

Tunable potential wells
Separated by tunable tunnel barrier



Charge qubit components

1. Quantum dots
2. Source/drain leads
3. Tunneling gaps
4. Gates
 - Plungers to tune chemical potentials (definitely)
 - Barrier gates to tune tunnel barriers/rates
5. A passive charge-state readout circuit e.g. SET or QPC

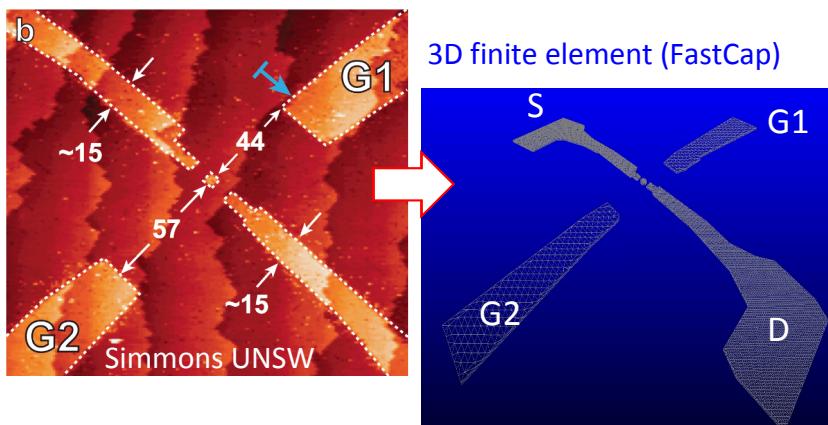
All elements are coplanar → crowding limits number of device elements

Electrostatic & transport modeling for qubit design

- Quantitative models have been demonstrated for donor devices
- NEMO (G. Klimeck): Atomistic detail, quantum properties...
- For charge qubit: use finite element models (FastCap) + transport model (CapNet)

Electrostatics modeling

6-7 donor dot (Fuechsle, Nature Nano 2010)

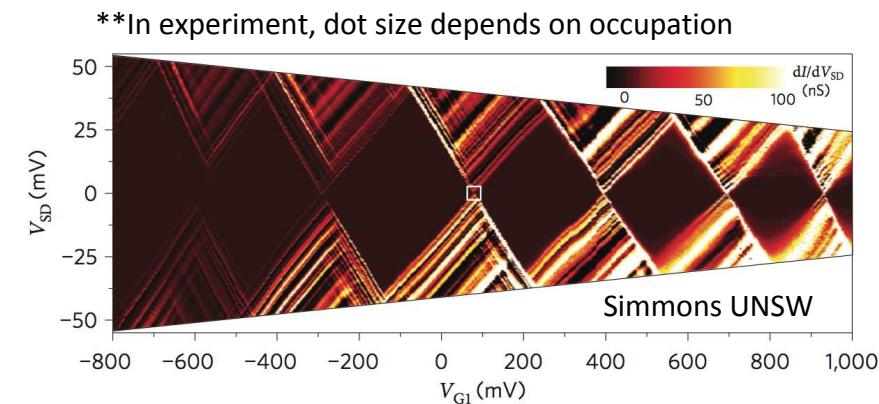


Dot capacitances (aF) & gate lever arms

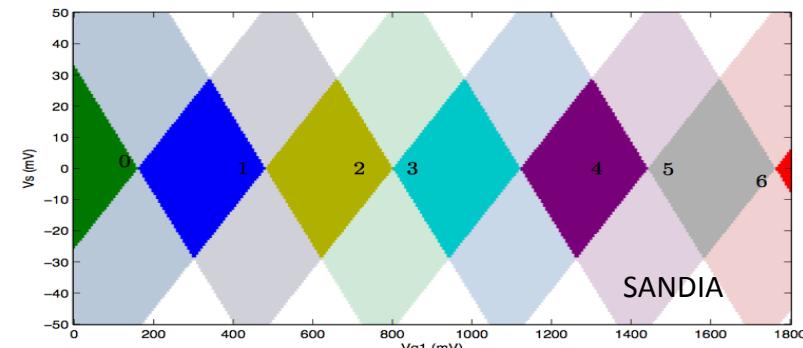
	C_S	C_D	C_{G1}	C_{G2}	α_{G1}	α_{G2}
Experiment UNSW*	2.32	1.93	0.53	0.38	0.10	0.07
FastCap UNSW*	2.08	1.90	0.51	0.43	0.10	0.09
FastCap SNL	2.2	2.1	0.50	0.44	0.10	0.08

Quantitative agreement between model/experiment

Transport experiment and model

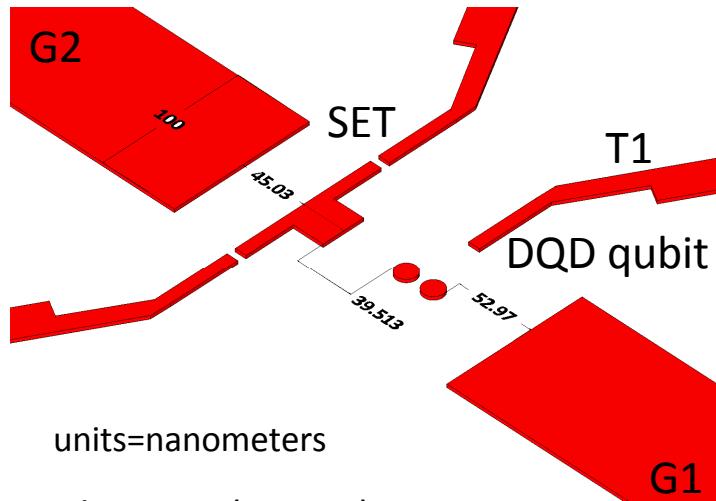


Transport (CapNet) (E. Nielsen, R. Rahman, SNL)

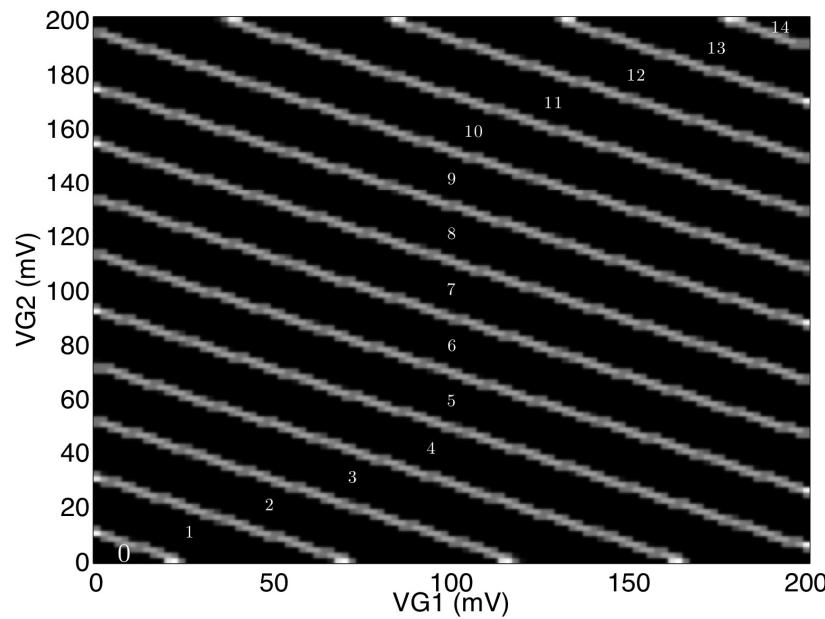


$E_c \sim 25-50$ meV vs $E_c \sim 30$ meV (Model)

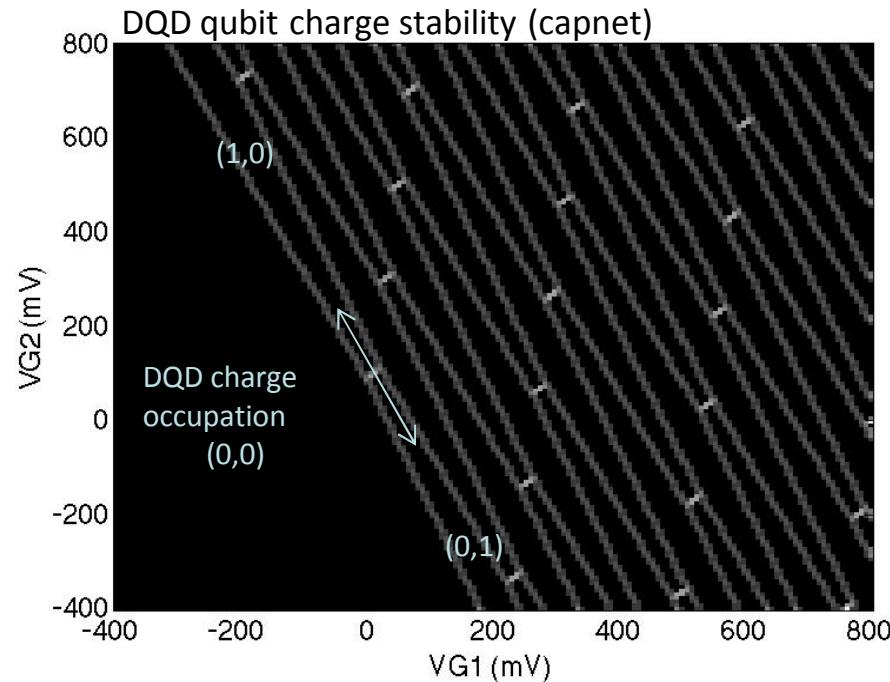
Initial charge qubit designs



Readout SET (capnet)



Charge transfer signals 3 – 6% ($\Delta VG_2 = 0.6\text{--}1.2$ mV)



- Many DQD charge states accessible in a realistic range of VG_1 & VG_2
- The SET has many more charge states in the same VG_1 & VG_2 range
- Charge transfer signals of 3-6% suggest SET will be sensitive electrometer of qubit state

Milestones for STM fab



- **Year 1**
 - Recover old STM chamber outside of clean room for non-toxic gas experiments
 - Design clean room STM (includes phosphine capability)
 - Build clean room STM
 - Show clean hydrogen terminated surface and local removal with STM tip
- **Year 2**
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Progress on fabrication steps

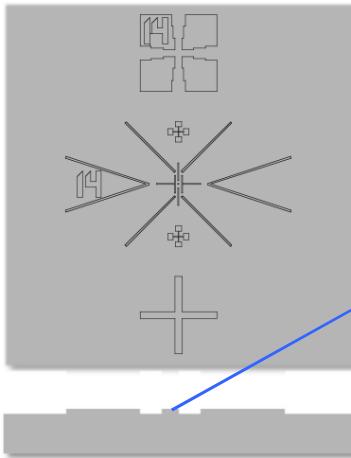
Testing PH₃
system

1. Start w clean
Si(001)

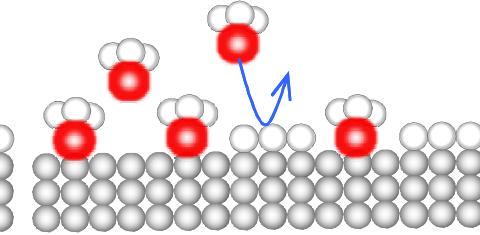
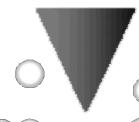
2. Adsorb H resist
Self-limiting 1 monolayer

3. Pattern w STM
Atomic-precision

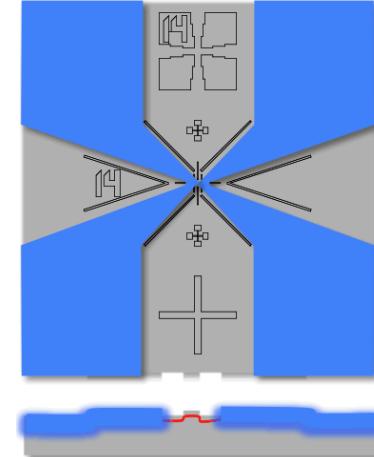
4. Adsorb PH₃



Etched alignment marks
J. Dominguez



Al depo+lift off
J. Dominguez



5. Incorporate P
-Anneal \rightarrow Si-P swap
-H resist constrains P

6. Desorb H
anneal

7. Bury P in Si

8. Add contacts

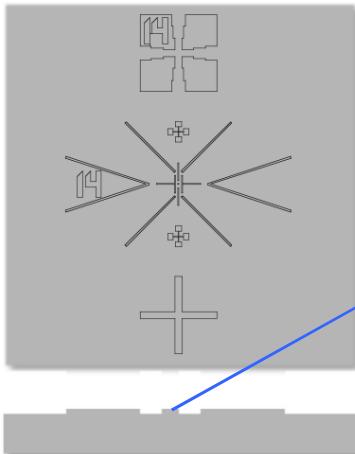
Progress on fabrication steps

1. Start w clean
Si(001)

2. Adsorb H resist
Self-limiting 1 monolayer

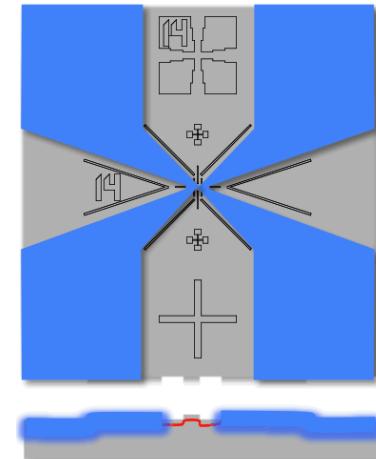
3. Pattern w STM
Atomic-precision

4. Adsorb PH₃



Etched alignment marks
J. Dominguez

Al depo+lift off
J. Dominguez



5. Incorporate P
-Anneal \rightarrow Si-P swap

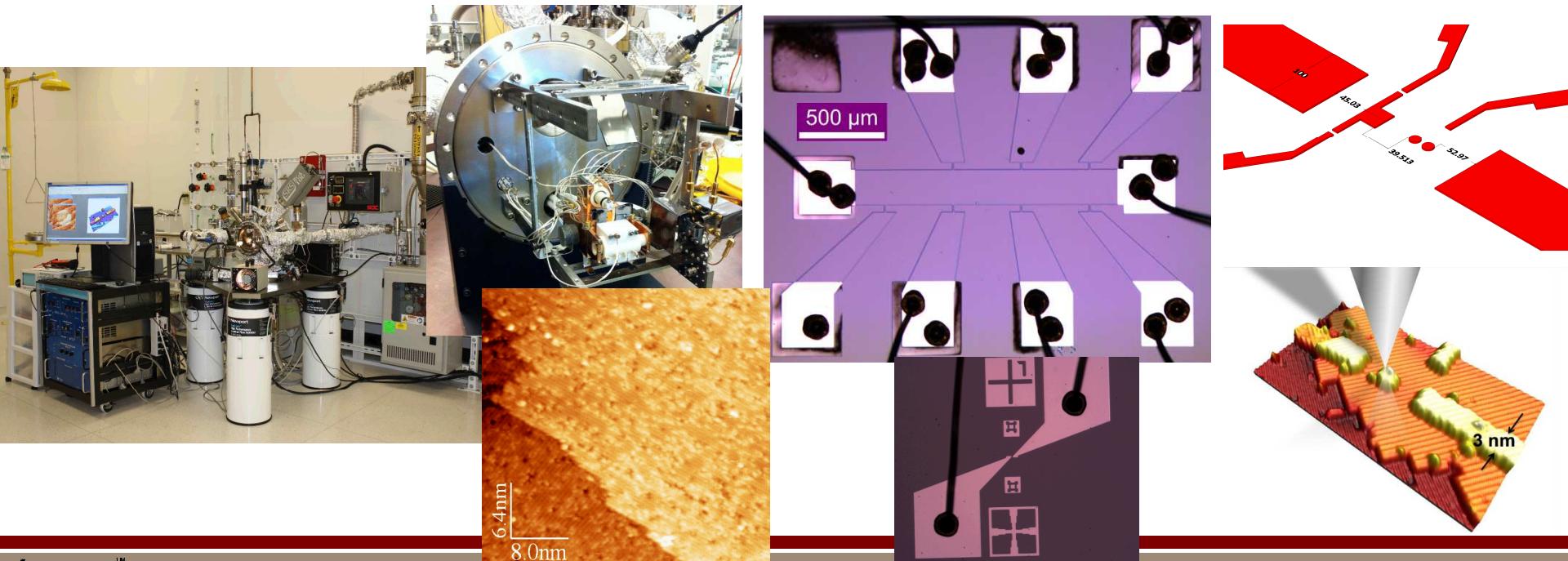
6. Desorb H
anneal

7. Bury P in Si

8. Add contacts

Summary of work

- Completed new lab and phosphine installation & testing
- Completed new STM, installed into cleanroom lab
- Fabricated our first macroscopic test devices in the new lab
 - Performed 4K cryogenic characterization of devices
 - Demonstrated P donor incorporation and encapsulation
- With Simmons fab steps reproduced in our lab, we are working to demonstrate atomic-precision STM fabricated devices via full Simmons process (in-progress)
- Design and modeling of initial qubit designs (in-progress)



Approach to qubit design

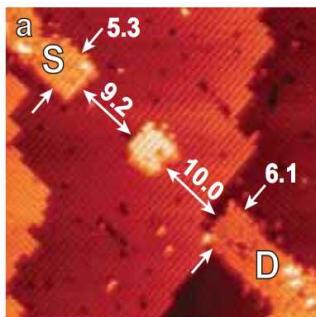
- Identify necessary components for the qubit
- Study Simmons devices and tabulate design rules for device components
 - feature sizes and layouts
 - mutual capacitances
 - gate lever arms
 - gate voltage ranges (leakage limits)
 - tunneling rate estimates (source-dot-drain, dot-dot)
 - charge sensor design and layout
- Identify initial design rules and also potential design challenges/issues for a charge qubit device
 - Optimal feature size and position for good coupling strengths (capacitive and tunnel couplings)
 - Charge sensing, readout QPC versus SET
 - Crowding of device elements in plane
 - Crowding of metal leads on top surface
 - Power dissipation (joule heating, electrons are moving in confined spaces)
and dot leading to temperature variation
 - For a 27-nm-wide wire, 100 nA current threshold for heating (Ruess PRB 2007)
 - For 5 nm wide wire expect about 20 nA upper bound on current
- Using Simmons designs as a starting point, propose some planar designs for a few D qubit,
 - For Simmons devices, FASTCAP matches quantitatively with experimental data (predictive quantitative electrostatic modeling of proposed designs may be possible)
 - It would also be ideal to estimate tunneling rates for a given design.
(Even just estimates of *relative* tunnel rates)

Qubit design starting points

Charge qubit components

1. Quantum dots
2. Source/drain leads and tunneling gaps
3. Gates
 - Plungers to tune chemical potentials (definitely)
 - Barrier gates to tune tunnel barriers/rates
4. Charge-state readout e.g. SET or QPC

Dots: few electron



UNSW
units=nm

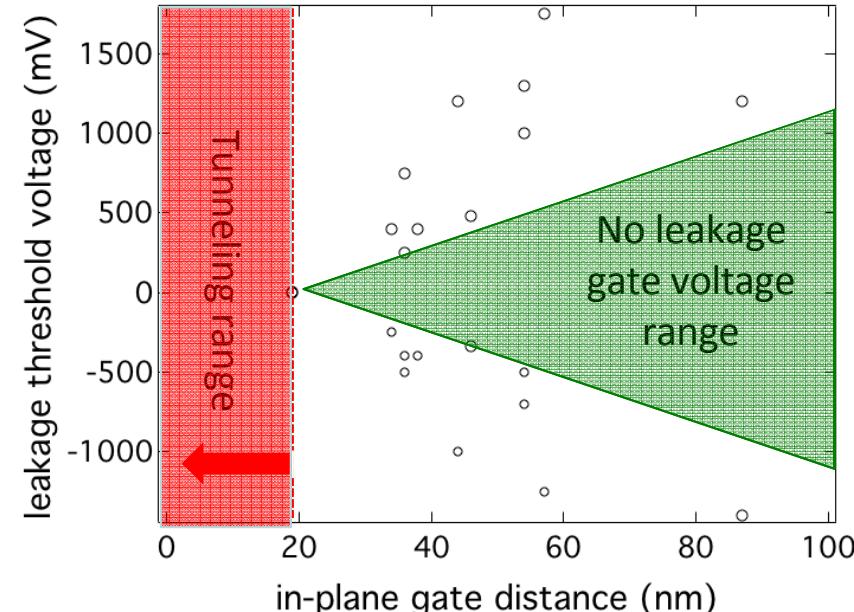
Source & Drain: 4-7 nm-wide lines

2D planar Lithographic delta-dope devices in Si:

Design= What shape? Size?
How far apart?

Gates: 50+ nm wide rectangles (Simmons)

Gate isolation gaps:



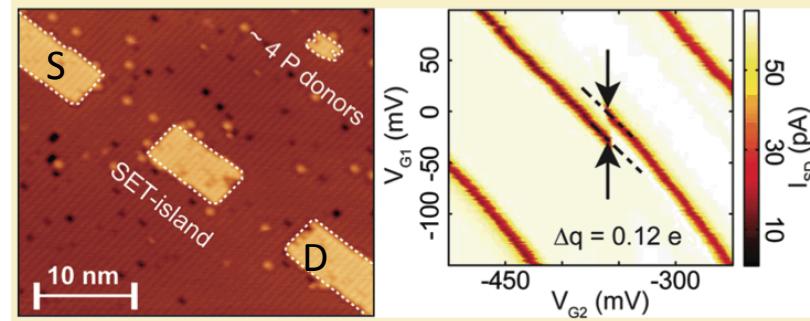
Tunnel Junctions: 8-10 nm

Charge sensor for qubit state

- SET has been demonstrated (12% charge transfer signal)
- Still no demonstration of charge sensing via QPC

Charge sense via SET

Mahapatra...Simmons Nano Lett 11, 4376 (2011)



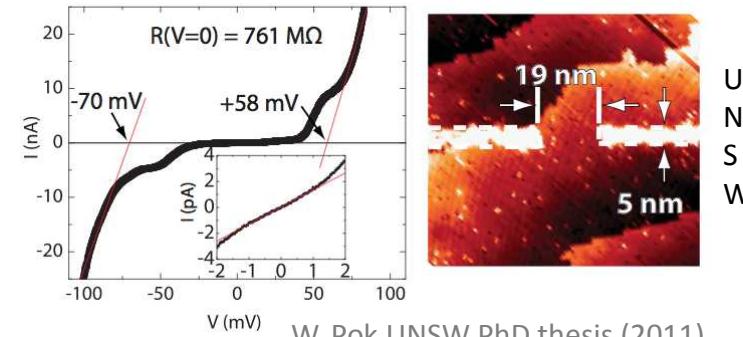
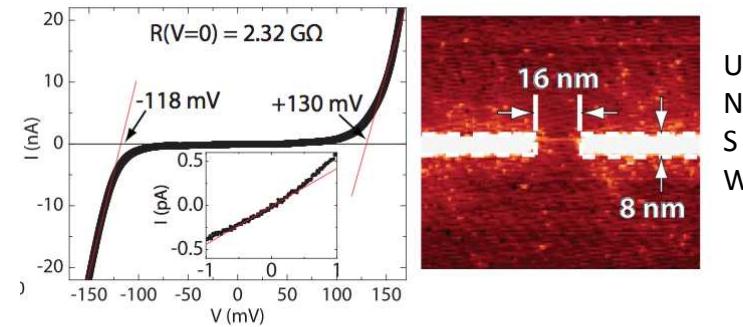
Single e^- on 4 donor dot induces
V equivalent to 0.12 e^- on SET dot

→ abrupt change in SET S-D current



Charge sense via QPC (??)

Tunnel gaps have been characterized



W. Pok UNSW PhD thesis (2011)

Charge sensing via QPC not yet demonstrated, QPC may require less leads